

Search Notes

Application/Control No.

10/820,164

Examiner

M. Lee

Applicant(s)/Patent under
Reexamination

YUEN ET AL.

Art Unit

2622

SEARCHED

Class	Subclass	Date	Examiner
348	564-569	8/25/2006	ML
725	43-44		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	8/25/2006	ML